

Date Created : 2008/05/07
Date Issued On : 2008/05/14
PCN# : Q2081901

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:
Name: LEE, JEANHEE
E-mail: JEANHEE.LEE@fairchildsemi.com
Phone:

PCN Originator:
Name: LEE, JEANHEE
E-mail: JEANHEE.LEE@fairchildsemi.com
Phone:

Implementation of change:
Expected 1st Device Shipment Date: 2008/08/10

Earliest Year/Work Week of Changed Product: WW33

Change Type Description: Wafer Diameter

Description of Change (From): 4inch Diameter, Selected Rectifier products currently manufactured using the 4-inch line in Bucheon. Korea. adress:82-3, Dodang-doing, Wonmi-gu, Gyeonggi-do, Korea

Description of Change (To): 5inch Diameter Selected Rectifier products currently manufactured using the 5-inch line in Bucheon. Korea. adress:82-3, Dodang-doing, Wonmi-gu, Gyeonggi-do, Korea There will be no additional changes to the layout, die size, geometry, sunbstrate.

Reason for Change : Fab line transfer

Qual/REL Plan Numbers : Q20050133

all item pass

Qualification :

all item pass

Results/Discussion

Test: (Autoclave)					
Lot	Device	96-HOURS	Failure Code		
Q20050133AAACLV	RURG8060	0/77			
Test: (High Temperature Reverse Bias)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code

Q20050133AAHTRB	RURG8060	0/77			
			0/77		
				0/77	
Test: (High Temperature Storage Life)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20050133AAHTSL	RURG8060	0/77			
			0/77		
				0/77	
Test: (Human Body Model ESD)					
Lot	Device	Results	Failure Code		
Q20050133AAHBM	RURG8060	0/3			
Test: (Machine Model ESD)					
Lot	Device	Results	Failure Code		
Q20050133AAMM	RURG8060	0/3			
Test: (Temperature Humidity Biased Test)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20050133AATHBT	RURG8060	0/77			
			0/77		
				0/77	
Test: -65C, 150C (Temperature Cycle)					
Lot	Device	200-CYCLES	500-CYCLES	Failure Code	
Q20050133AATMCL1	RURG8060	0/77			
Q20050133AATMCL1	RURG8060		0/77		

Product Id Description : these are rectifiers for wafer biz

Affected FSIDs :

FF10UP30APWD	FF20UP30PWD	FF30HP120PWD
FF30UP30APWD	FF40HP60PWD	FF50UP60PWD
FF75HP120PWD	FF80UP60PWD	ISL9R18120W2
ISL9R30120W2	ISL9R860W2	PCFF04S60W
PCISL9R1560W	PCISL9R18120W	PCISL9R30120W
PCISL9R3060F	PCISL9R460W	PCISL9R860W
PCRH1560W	PCRH3060F	PCRH75120W
PCRU8060W		